

### **Description**

The DMG7408SFG uses advanced trench technology

to provide excellent R<sub>DS(ON)</sub>, low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

#### **General Features**

 $V_{DS} = 30V I_{D} = 20 A$ 

 $R_{DS(ON)}$  < 20m $\Omega$  @  $V_{GS}$ =10V

#### **Application**

Battery protection

Load switch

Uninterruptible power supply

### **Package Marking and Ordering Information**

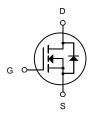
Product ID	Pack	Brand	Qty(PCS)
DMG7408SFG	DFN3X3-8L	HXY MOSFET	5000

### Absolute Maximum Ratings (T<sub>c</sub>=25 ℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	30	V
VGS	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	20	Α
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	8	Α
IDM	Pulsed Drain Current <sup>2</sup>	38	Α
EAS	Single Pulse Avalanche Energy <sup>3</sup>	28	mJ
IAS	Avalanche Current	13.8	Α
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation⁴	5.5	W
TSTG	Storage Temperature Range	-55 to 175	°C
TJ	Operating Junction Temperature Range	-55 to 175	°C
R <sub>θ</sub> JC	Thermal Resistance Junction-Case <sup>1</sup>	36	°C/W



DFN3X3-8L



N-Channel MOSFET



# **Electrical Characteristics** (T<sub>J</sub>=25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	30	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =30V, V <sub>GS</sub> = 0V,	-	_	1.0	μA
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{DS}$ =0V, $V_{GS}$ = ±20V	-	-	±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.0	1.5	2.5	V
D	Static Drain-Source on-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =5A	-	15	20	mΩ
$R_{DS(on)}$	note3	V <sub>GS</sub> =4.5V, I <sub>D</sub> =3A	-	21	29	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1.0MHz	-	490	-	pF
Coss	Output Capacitance		-	79	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	61	-	pF
Qg	Total Gate Charge	V <sub>DS</sub> =15V, I <sub>D</sub> =5.8A, V <sub>GS</sub> =10V	-	10	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	1.7	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	2.5	-	nC
t <sub>d(on)</sub>	Turn-on Delay Time		-	6	-	ns
t <sub>r</sub>	Turn-on Rise Time	$V_{DS}$ =15V, $I_{D}$ =3A, $V_{GS}$ =10V, $R_{REN}$ =3Ω	-	15	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time		-	17	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	17	-	ns
Is	Maximum Continuous Drain to Source Diode Forward Current		-	-	9	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	36	Α
$V_{\text{SD}}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =9A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time		-	7	-	ns
Qrr	Body Diode Reverse Recovery Charge	I <sub>F</sub> =5A, dI/dt=100A/µs	-	2	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

- 2. EAS condition :  $T_J$ =25°C, $V_{DD}$ =15V, $V_G$ =10V,L=0.5mH,Rg=25 $\Omega$ , $I_{AS}$ =6A
- 3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%



# **Typical Performance Characteristics**

Figure1: Output Characteristics

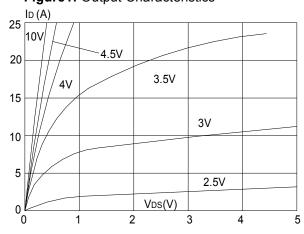


Figure 2: Typical Transfer Characteristics

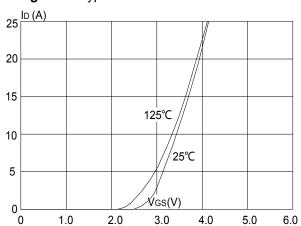


Figure 3:On-resistance vs. Drain Current RDS(ON) ( $m\Omega$ )

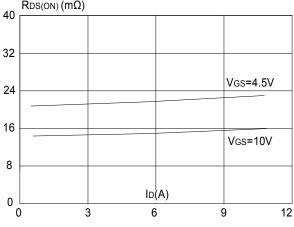


Figure 4: Body Diode Characteristics

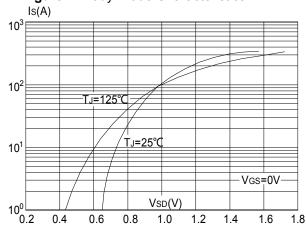


Figure 5: Gate Charge Characteristics

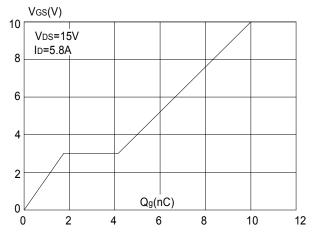
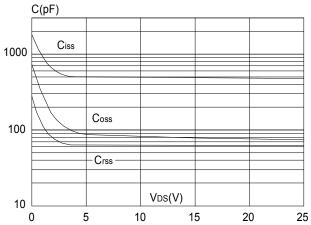


Figure 6: Capacitance Characteristics





**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature

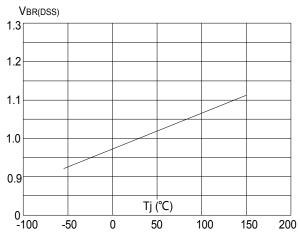
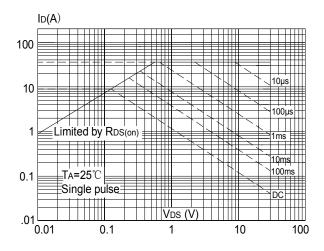
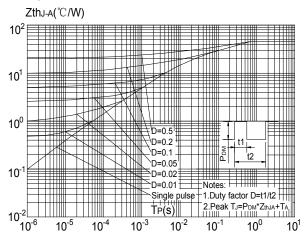


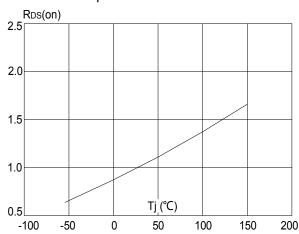
Figure 9: Maximum Safe Operating Area



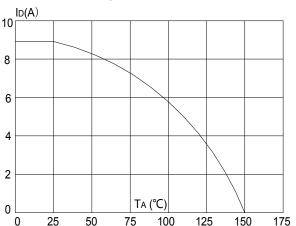
**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient



**Figure 8:** Normalized on Resistance vs. Junction Temperature



**Figure 10:** Maximum Continuous Drain Current vs. Ambient Temperature





### **Test Circuit**

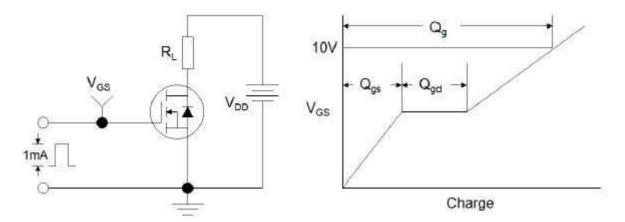


Figure1:Gate Charge Test Circuit & Waveform

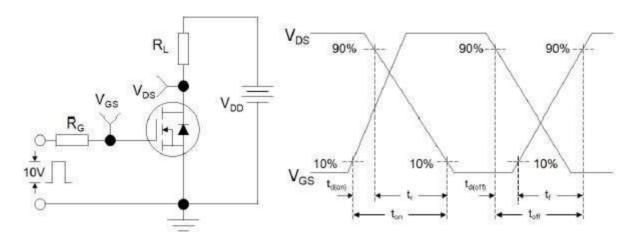


Figure 2: Resistive Switching Test Circuit & Waveforms

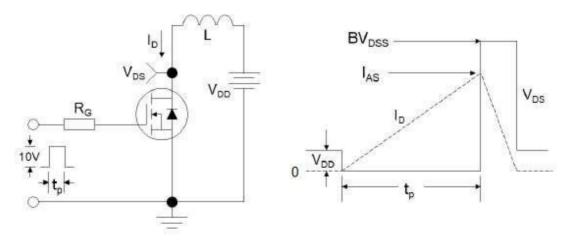
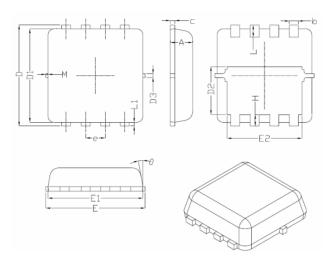


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms



## **DFN3X3-8L Package Information**



Symbol	Dimensions In Millimeters		
Symbol	Min.	Nom.	Max.
A	0.70	0.75	0.80
b	0.25	0.30	0.35
С	0.10	0.15	0.25
D	3.25	3.35	3.45
D1	3.00	3.10	3.20
D2	1.48	1.58	1.68
D3	-	0.13	-
E	3.20	3.30	3.40
E1	3.00	3.15	3.20
E2	2.39	2.49	2.59
е	0.65BSC		
Н	0.30	0.39	0.50
L	0.30	0.40	0.50
L1	-	0.13	-
M	*	*	0.15
θ		10 <sup>°</sup>	12 <sup>°</sup>



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